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Preface

This volume contains the proceedings of the 16th IFIP TC6/WG6.1 International Conference on Testing of Communicating Systems (TestCom 2004). This conference was held at St Anne's College, Oxford, UK, from March 17 to March 19, 2004.

TestCom 2004 was the sixteenth in a series of IFIP-sponsored events that started in 1988. The previous events were held in Vancouver, Canada (1988); Berlin, Germany (1989); McLean, USA (1990); Leidschendam, Netherlands (1991); Montreal, Canada (1992); Pau, France (1993); Tokyo, Japan (1994); Evry, France (1995); Darmstadt, Germany (1996); Cheju Island, Korea (1997); Tomsk, Russia (1998); Budapest, Hungary (1999); Ottawa, Canada (2000); Berlin, Germany (2002); and Sophia Antipolis, France (2003). TestCom was not held in 2001 since at this point the conference moved from autumn to spring.

TestCom 2004 was organized by Brunel University, UK and LSR-IMAG, France and was sponsored by IFIP. Support was also provided by the Engineering and Physical Sciences Research Council (EPSRC). We are grateful to the keynote speaker, Prof. Sir Tony Hoare, FRS, and our invited speakers for agreeing to address TestCom 2004.

TestCom focuses on the testing of communicating systems within all application domains. Examples of such application domains include, but are not limited to, the automobile industry, avionics, banking, e-commerce, health, military, and telecommunications systems. The 14 papers contained in this volume are largely motivated by problems within the telecommunications domain, which is not surprising given the origins of TestCom. However, a number of papers cover topics outside of telecommunications, such as the testing of reactive systems and testing from UML. This is encouraging and we hope that it indicates the beginning of a closer dialogue between the telecommunications testing community and the general software testing community.

We are grateful to the many people who contributed to the activities required in order for TestCom 2004 to be held. These people include the members of the steering committee, who provided invaluable advice, and the members of the organizing committee, who were responsible for the smooth running of TestCom 2004. As ever, the referees were given the vital task of reviewing many papers in a short period of time. The individuals who contributed to this are listed in the following pages. We would also like to thank Ursula Barth of Springer-Verlag for her assistance in the production of this volume.

January 2004

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